IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

| In re Application of: |) | F : D C 1 |
|------------------------------------|--------|-----------------------|
| MANABU KOMATSU ET AL. | ; | Examiner: B. Gordon |
| | : | Group Art Unit: 1743 |
| Application No.: 10/553,660 |) : | Confirmation No. 4672 |
| Int'l Appln. No. PCT/JP2004/019716 |) | |
| Filed: December 22, 2004 | ; | |
| For: TEST SPECIMEN AND |) | D 1 10 0006 |
| PRODUCTION THEREOF | : | December 13, 2006 |

Mail Stop PCT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

SECOND INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the attached Form PTO-1449. Since the U.S. Patent and Trademark Office waived the requirement under 37 C.F.R. § 1.98 (a)(2)(i) for submitting a copy of each cited U.S. patent and each U.S. patent application publication for all U.S. national patent applications and for all international applications that have entered the national stage under 35 U.S.C. § 371, no copies of such documents are provided. Copies of the other documents are submitted herewith.

The concise explanation of relevance for the non-English documents may be found, *inter alia*, in the English language abstracts attached thereto and/or in the specification where they are cited. Also, the concise explanation of relevance for JP 2000-251665 and JP 11-187900 may be found, respectively, in related U.S. Patent Nos. 6,579,139 B1 and 6,476,215 B1.

CONCLUSION

It is respectfully requested that the above information be considered by the

Examiner and that a copy of the attached Form PTO-1449 be returned indicating that such

information has been considered.

Applicants' undersigned attorney may be reached in our New York office by

telephone at (212) 218-2100. All correspondence should continue to be directed to our

address given below.

Respectfully submitted,

/Jason M. Okun/

Jason M. Okun

Attorney for Applicants Registration No.: 48,512

FITZPATRICK, CELLA, HARPER & SCINTO

30 Rockefeller Plaza

New York, New York 10112-3801

Facsimile: (212) 218-2200

- 2 -

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)

ATTY DOCKET NO. 03500.103123 APPLICATION NO. 10/553,660

APPLICANT

Manabu Komatsu et al.

FILING DATE December 22, 2004 GROUP

1743 U.S. PATENT DOCUMENTS *EXAMINER INITIAL DOCUMENT FILING DATE IF APPROPRIATE NUMBER DATE CLASS SUBCLASS NAME 5,365,563 11/15/94 Kira et al. 378 48 6,579,139 B1 06/17/03 Mishima et al. 445 24 6,476,215 B1 11/05/02 Okamoto et al. 536 25.3 FOREIGN PATENT DOCUMENTS TRANSLATION YES/NO/ OR ABSTRACT DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS JP 2000-251665 09/14/00 **Abstract** Japan JP 11-187900 07/13/99 **Abstract** Japan JP 4-361055 12/14/92 **Abstract** Japan OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) Paolo Lazzeri et al., "Use of Spin-Coated TXRF Reference Samples for ToF-SIMS Metal Contaminant Quantification on Silicon Wafers," 29 Surf. Interface Anal. 798-803 (2000). **EXAMINER** DATE CONSIDERED

| Sheet | 1 | of | 1 |
|-------|---|----|---|
| Sheer | | OΤ | |

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.